Notice of References Cited Application/Control No. 10/718,561 Examiner Leslie J. Evanisko Applicant(s)/Patent Under Reexamination BAEK ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2002/0109799	08-2002	Choi et al.	349/43
	В	US-2003/0084796	05-2003	Kwon et al.	101/41
	С	US-2004/0119935	06-2004	Baek et al.	349/187
	D	US-			
	Е	US-	-		
	F	US-			
	G	US-			
	Н	US-			
	-	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	υ						
	٧						
	w						
	х						

^{*}A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.